CMOS Digital Integrated Circuits Silicon Monolithic

## 74HC175D

#### 1. Functional Description

· Quad D-Type Flip-Flop with Clear

#### 2. General

The 74HC175D is a high speed CMOS D-TYPE FLIP FLOP fabricated with silicon gate C2MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

Information signals applied to D inputs are transferred to the Q and  $\overline{Q}$  outputs on the positive going edge of the clock pulse.

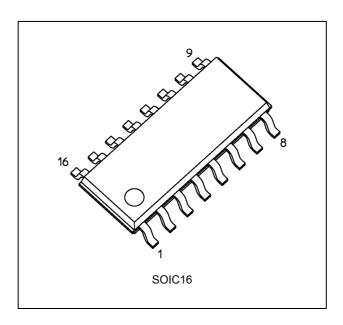
When the  $\overline{CLR}$  input is held low, the Q outputs are at the low logic level and the  $\overline{Q}$  outputs are at the high logic level independent of the other inputs.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

#### 3. Features

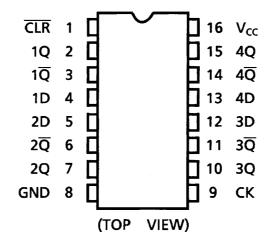
- (1) High speed:  $f_{MAX} = 63 \text{ MHz}$  (typ.) at  $V_{CC} = 5 \text{ V}$
- (2) Low power dissipation:  $I_{CC} = 4.0 \mu A \text{ (max)}$  at  $T_a = 25 \text{ °C}$
- (3) Balanced propagation delays:  $t_{PLH} \approx t_{PHL}$
- (4) Wide operating voltage range:  $V_{CC(opr)} = 2.0 \text{ V}$  to 6.0 V

### 4. Packaging

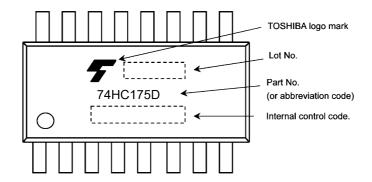




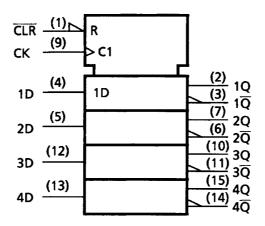
### 5. Pin Assignment



### 6. Marking



## 7. IEC Logic Symbol



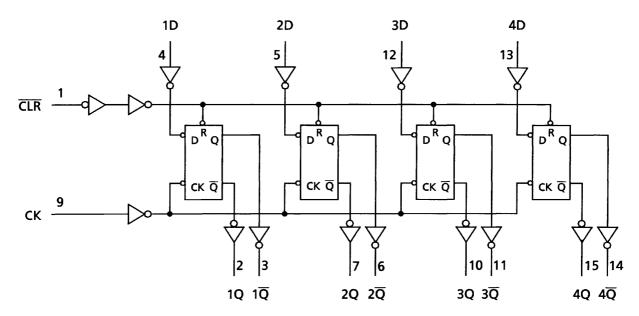
## 8. Truth Table

	Inputs			puts	Function		
CLR	D	СК	Q	Ια	Function		
L	Х	Х	L	Н	Clear		
Н	L		L	Н			
Н	Н		Н	L	_		
Н	Х		Qn	$\overline{Q}_n$	No Change		

X: Don't care



### 9. System Diagram



### 10. Absolute Maximum Ratings (Note)

Characteristics	Symbol	Note	Rating	Unit
Supply voltage	V <sub>CC</sub>		-0.5 to 7.0	V
Input voltage	V <sub>IN</sub>		-0.5 to V <sub>CC</sub> + 0.5	V
Output voltage	V <sub>out</sub>		-0.5 to V <sub>CC</sub> + 0.5	V
Input diode current	I <sub>IK</sub>		±20	mA
Output diode current	I <sub>OK</sub>		±20	mA
Output current	I <sub>OUT</sub>		±25	mA
V <sub>CC</sub> /ground current	I <sub>CC</sub>		±50	mA
Power dissipation	P <sub>D</sub>	(Note 1)	500	mW
Storage temperature	T <sub>stg</sub>		-65 to 150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: P<sub>D</sub> derates linearly with -8 mW/°C above 85 °C

### 11. Operating Ranges (Note)

Characteristics	Symbol	Test Condition	Rating	Unit
Supply voltage	V <sub>CC</sub>	ı	2.0 to 6.0	V
Input voltage	V <sub>IN</sub>	I	0 to V <sub>CC</sub>	V
Output voltage	V <sub>OUT</sub>		0 to V <sub>CC</sub>	V
Operating temperature	T <sub>opr</sub>		-40 to 125	°C
Input rise and fall times	t <sub>r</sub> ,t <sub>f</sub>		0 to 50	μS

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either  $V_{CC}$  or GND.



### 12. Electrical Characteristics

## 12.1. DC Characteristics (Unless otherwise specified, T<sub>a</sub> = 25 °C)

Characteristics	Symbol	Test Condition	ı	V <sub>CC</sub> (V)	Min	Тур.	Max	Unit
High-level input voltage	V <sub>IH</sub>	_		2.0	1.50	_	_	V
				4.5	3.15	_	_	
				6.0	4.20	_		
Low-level input voltage	V <sub>IL</sub>	_		2.0			0.50	V
				4.5	ı		1.35	
				6.0			1.80	
High-level output voltage	V <sub>OH</sub>	$V_{IN} = V_{IH}$ or $V_{IL}$	I <sub>OH</sub> = -20 μA	2.0	1.9	2.0	_	V
				4.5	4.4	4.5	_	
				6.0	5.9	6.0	_	
			I <sub>OH</sub> = -4 mA	4.5	4.18	4.31	_	
			$I_{OH} = -5.2 \text{ mA}$	6.0	5.68	5.80	_	
Low-level output voltage	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 20 μA	2.0	_	0.0	0.1	V
				4.5	_	0.0	0.1	
				6.0	_	0.0	0.1	
			I <sub>OL</sub> = 4 mA	4.5	_	0.17	0.26	
			I <sub>OL</sub> = 5.2 mA	6.0		0.18	0.26	
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND		6.0			±0.1	μА
Quiescent supply current	I <sub>CC</sub>	$V_{IN} = V_{CC}$ or GND		6.0	_	_	4.0	μΑ

## 12.2. DC Characteristics (Unless otherwise specified, $T_a$ = -40 to 85 °C)

Characteristics	Symbol	Test Condition	١	V <sub>CC</sub> (V)	Min	Max	Unit
High-level input voltage	V <sub>IH</sub>	_		2.0	1.50	_	V
				4.5	3.15	_	
				6.0	4.20	_	
Low-level input voltage	V <sub>IL</sub>	_		2.0	_	0.50	V
				4.5	_	1.35	
				6.0	_	1.80	
High-level output voltage	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -20 μA	2.0	1.9	_	V
				4.5	4.4	_	
				6.0	5.9	_	
			$I_{OH} = -4 \text{ mA}$	4.5	4.13	_	
			$I_{OH} = -5.2 \text{ mA}$	6.0	5.63	_	
Low-level output voltage	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 20 μA	2.0		0.1	V
				4.5	_	0.1	
				6.0	_	0.1	
			I <sub>OL</sub> = 4 mA	4.5	_	0.33	
			I <sub>OL</sub> = 5.2 mA	6.0	_	0.33	
Input leakage current	I <sub>IN</sub>	$V_{IN} = V_{CC}$ or GND		6.0		±1.0	μА
Quiescent supply current	I <sub>CC</sub>	$V_{IN} = V_{CC}$ or GND		6.0	_	40.0	μА



## 12.3. DC Characteristics (Unless otherwise specified, $T_a$ = -40 to 125 °C)

Characteristics	Symbol	Test Condition	n	V <sub>CC</sub> (V)	Min	Max	Unit
High-level input voltage	V <sub>IH</sub>	_		2.0	1.50	_	V
				4.5	3.15	_	
				6.0	4.20	_	
Low-level input voltage	V <sub>IL</sub>	_		2.0	_	0.50	V
				4.5		1.35	
				6.0		1.80	
High-level output voltage	V <sub>OH</sub>	$V_{IN} = V_{IH}$ or $V_{IL}$	I <sub>OH</sub> = -20 μA	2.0	1.9		V
				4.5	4.4	_	
				6.0	5.9	_	
			$I_{OH}$ = -4 mA	4.5	3.7	_	
			I <sub>OH</sub> = -5.2 mA	6.0	5.2	_	
Low-level output voltage	V <sub>OL</sub>	$V_{IN} = V_{IH}$ or $V_{IL}$	I <sub>OL</sub> = 20 μA	2.0	_	0.1	V
				4.5	_	0.1	
				6.0	_	0.1	
			I <sub>OL</sub> = 4 mA	4.5	_	0.4	
			I <sub>OL</sub> = 5.2 mA	6.0	_	0.4	
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND		6.0	_	±1.0	μА
Quiescent supply current	I <sub>CC</sub>	$V_{IN} = V_{CC}$ or GND		6.0	_	160.0	μА



## 12.4. Timing Requirements (Unless otherwise specified, $T_a = 25$ °C, Input: $t_f = t_f = 6$ ns)

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Тур.	Limit	Unit
Minimum pulse width	$t_{w(L)}, t_{w(H)}$	_	2.0	_	75	ns
(CK)			4.5	_	15	
			6.0	_	13	
Minimum pulse width	t <sub>w(L)</sub>	_	2.0	_	75	ns
(CLR)			4.5	_	15	
			6.0	_	13	1
Minimum setup time	t <sub>S</sub>	_	2.0	_	75	ns
			4.5	_	15	
			6.0	_	13	1
Minimum hold time	t <sub>h</sub>	_	2.0	_	0	ns
			4.5	_	0	
			6.0	_	0	
Minimum removal time	t <sub>rem</sub>	_	2.0	_	75	ns
			4.5	_	15	
			6.0	_	13	1
Clock frequency	f	_	2.0	_	6	MHz
			4.5	_	31	] <b> </b>
			6.0	_	36	

# 12.5. Timing Requirements (Unless otherwise specified, $T_a$ = -40 to 85 °C, Input: $t_r$ = $t_f$ = 6 ns)

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Limit	Unit
Minimum pulse width	$t_{w(L)},t_{w(H)}$	_	2.0	95	ns
(CK)			4.5	19	
			6.0	16	
Minimum pulse width	t <sub>w(L)</sub>	_	2.0	95	ns
(CLR)			4.5	19	
			6.0	16	
Minimum setup time	t <sub>S</sub>	_	2.0	95	ns
			4.5	19	
			6.0	16	
Minimum hold time	t <sub>h</sub>	_	2.0	0	ns
			4.5	0	
			6.0	0	
Minimum removal time	t <sub>rem</sub>	_	2.0	95	ns
			4.5	19	
			6.0	16	
Clock frequency	f	_	2.0	5	MHz
			4.5	25	
			6.0	29	



# 12.6. Timing Requirements (Unless otherwise specified, $T_a$ = -40 to 125 °C, Input: $t_f$ = t<sub>f</sub> = 6 ns)

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Limit	Unit
Minimum pulse width	$t_{w(L)}, t_{w(H)}$	_	2.0	110	ns
(CK)			4.5	22	
			6.0	19	
Minimum pulse width	t <sub>w(L)</sub>	_	2.0	110	ns
(CLR)			4.5	22	
			6.0	19	
Minimum setup time	t <sub>S</sub>	_	2.0	110	ns
			4.5	22	
			6.0	19	
Minimum hold time	t <sub>h</sub>	_	2.0	0	ns
			4.5	0	
			6.0	0	
Minimum removal time	t <sub>rem</sub>	_	2.0	110	ns
			4.5	22	
			6.0	19	
Clock frequency	f	_	2.0	4	MHz
			4.5	20	
			6.0	24	

# 12.7. AC Characteristics (Unless otherwise specified, $C_L$ = 15 pF, $V_{CC}$ = 5 V, $T_a$ = 25 °C, Input: $t_r$ = $t_f$ = 6 ns)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Output transition time	$t_{TLH}, t_{THL}$	_	_	4	8	ns
Propagation delay time (CK-Q, $\overline{Q}$ )	t <sub>PLH</sub> ,t <sub>PHL</sub>	_	_	16	24	ns
Propagation delay time (CLR-Q, Q)	t <sub>PLH</sub> ,t <sub>PHL</sub>	_	_	13	21	ns
Maximum clock frequency	f <sub>MAX</sub>	_	36	63	_	MHz



# 12.8. AC Characteristics (Unless otherwise specified, $C_L$ = 50 pF, $T_a$ = 25 °C, Input: $t_r$ = $t_f$ = 6 ns)

Characteristics	Symbol	Note	Test Condition	V <sub>CC</sub> (V)	Min	Тур.	Max	Unit
Output transition time	t <sub>TLH</sub> ,t <sub>THL</sub>		_	2.0	_	30	75	ns
				4.5	_	8	15	
				6.0	_	7	13	
Propagation delay time (CK-Q, $\overline{\mathbf{Q}}$ )	t <sub>PLH</sub> ,t <sub>PHL</sub>		_	2.0	_	70	140	ns
				4.5		19	28	
				6.0	_	16	24	
Propagation delay time	t <sub>PLH</sub> ,t <sub>PHL</sub>		_	2.0	_	50	125	ns
$(\overline{CLR}-Q,\overline{Q})$				4.5		16	25	
				6.0	_	12	22	
Maximum clock frequency	f <sub>MAX</sub>		_	2.0	6	14	_	MHz
				4.5	31	53	_	
				6.0	36	63	_	
Input capacitance	C <sub>IN</sub>					3		pF
Power dissipation capacitance	C <sub>PD</sub>	(Note 1)	_		_	5	_	pF

Note 1: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation.

 $I_{CC(opr)} = C_{PD} \times V_{CC} \times f_{IN} + I_{CC}/4 \text{ (per F/F)}$ 

And the total C<sub>PD</sub> when n pcs of latch operate can be gained by the following equation.

 $C_{PD}$  (total) = 32 + 21 × n

# 12.9. AC Characteristics (Unless otherwise specified, $C_L = 50$ pF, $T_a = -40$ to 85 °C, Input: $t_r = t_f = 6$ ns)

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Min	Max	Unit
Output transition time	t <sub>TLH</sub> ,t <sub>THL</sub>	_	2.0	_	95	ns
			4.5	_	19	
			6.0		16	
Propagation delay time	t <sub>PLH</sub> ,t <sub>PHL</sub>		2.0		175	ns
(CK-Q, Q)			4.5	ı	35	
			6.0		30	
Propagation delay time	t <sub>PLH</sub> ,t <sub>PHL</sub>		2.0		160	ns
$(\overline{CLR}-Q,\overline{Q})$			4.5	ı	32	
			6.0		27	
Maximum clock frequency	f <sub>MAX</sub>		2.0	5	_	MHz
			4.5	25	_	
			6.0	29	_	



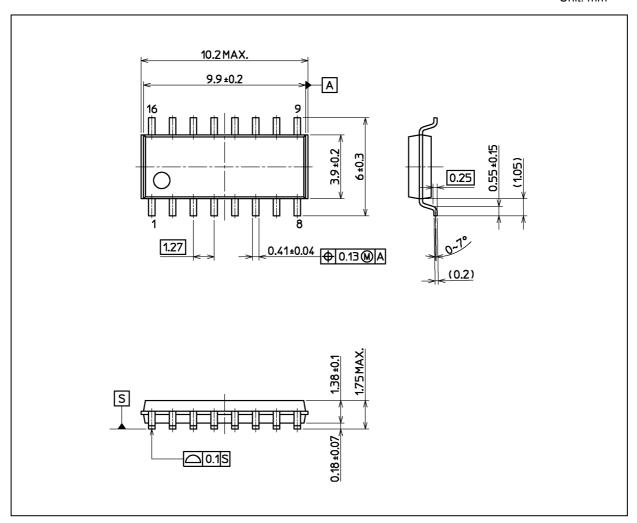
# 12.10. AC Characteristics (Unless otherwise specified, $C_L$ = 50 pF, $T_a$ = -40 to 125 °C, Input: $t_f$ = $t_f$ = 6 ns)

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Min	Max	Unit
Output transition time	t <sub>TLH</sub> ,t <sub>THL</sub>	_	2.0	_	110	ns
			4.5	_	22	
			6.0	_	19	
Propagation delay time (CK-Q, $\overline{\mathbf{Q}}$ )	t <sub>PLH</sub> ,t <sub>PHL</sub>	_	2.0	_	210	ns
			4.5	_	42	
			6.0	_	36	
Propagation delay time $(\overline{CLR}-Q, \overline{Q})$	t <sub>PLH</sub> ,t <sub>PHL</sub>	_	2.0	_	190	ns
			4.5	_	38	
			6.0	_	32	]
Maximum clock frequency	f <sub>MAX</sub>	_	2.0	4	_	MHz
			4.5	20	_	]
			6.0	24	_	



## **Package Dimensions**

Unit: mm



Weight: 0.15 g (typ.)

	Package Name(s)
Nickname: SOIC16	



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